

- ***X-RAY DIFFRACTOMETER
TECHNICAL SPECIFICATION***



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❖ MODEL NO	: PANalytical X-PERT PRO...
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❖ SOURCE OF X-RAYS	: Cu K α , 1.54 Angstrom. (wave length)
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❖ DETECTOR	: SCINTILLATION DETECTOR
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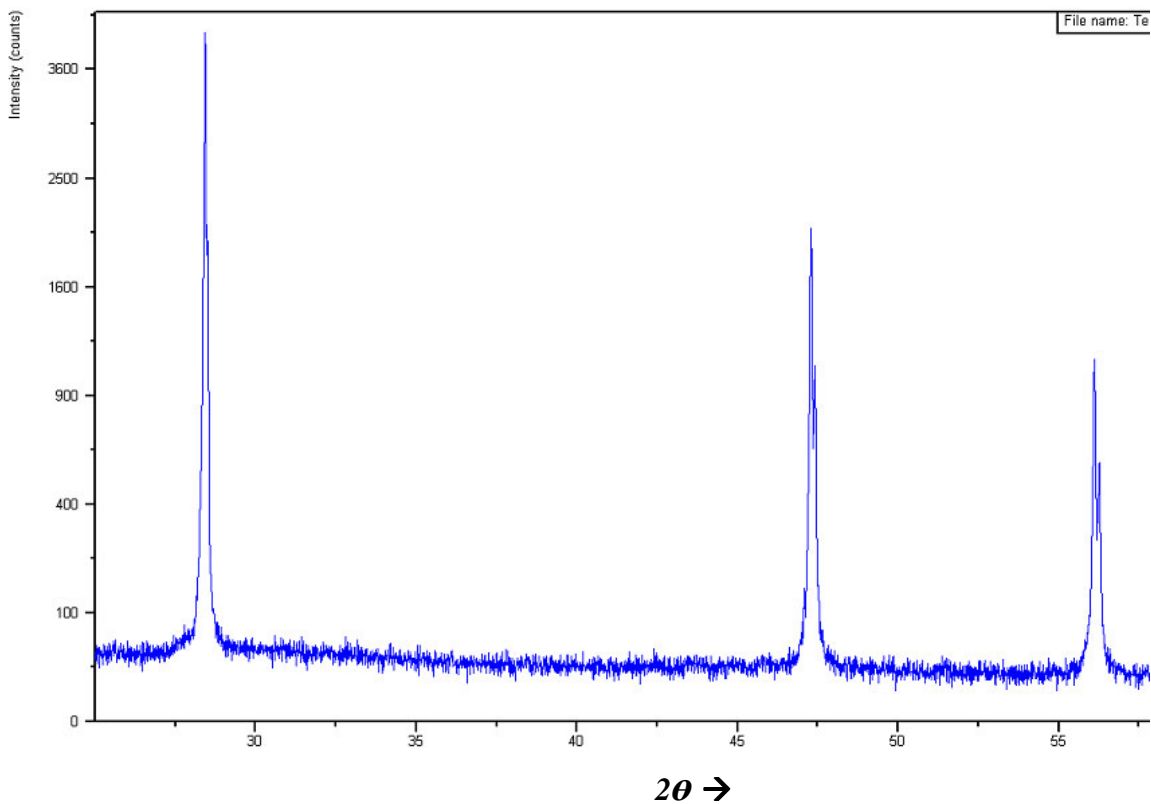
❖ SAMPLE STAGE	: FIXED, WITH X-RAY SOURCE & DETECTOR ROTATION.
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❖ **SAMPLE HOLDERS** : **SAMPLE HOLDERS ARE MADE OF ALUMINIUM , FOR POWDER SAMPLES WITH A VOLUME OF 15 mm×20 mm×1.8mm.**

❖ **ZERO BACKGROUND** : **ZERO BACKGROUND SAMPLE HOLDER IS AN OBLIQUELY CUTTED SILICON CRYSTAL WHICH CAN BE USED TO MOUNT VERY SMALL AMOUNT OF POWDER (≤ 1 mg), GLASS .. CAPILLARIES & FIBRES.**

❖ **MEASUREMENT RANGE:** **5 DEG TO 140 DEG.**

❖ **WORKING CONDITION** : **45 KV & 40 mA**



Intensity vs. 2θ plot of Si sample